

<b>Notice of References Cited</b>	Application/Control No. 10/710,642		Applicant(s)/Patent Under Reexamination ADKISSON ET AL.	
	Examiner Leigh Marie Garbowski		Art Unit 2825	Page 1 of 1

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*	B	US-2005/0138508	06-2005	Huisman et al.	714/726
*	C	US-7,007,214	02-2006	Eustis et al.	714/729
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**NON-PATENT DOCUMENTS**

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	V	MARINISSEN et al., "Creating Value Through Test," Design, Automation and Test in Europe Conference and Exhibition, IEEE 2003, pages 402-407.
	W	ZORIAN, "Optimizing Manufacturability by Design for Yield," July 14-16 2004 IEEE/SEMI Int'l Electronics Manufacturing Technology Symposium, 4 pages.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.